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Features

- ◆ Fully operational to +600 V
- Maximum Pulling Current: 0.45 A,
- Maximum Sinking Current: 1 A
- The High-Low Power Supply Has Independent UVLO Protection
- 10 V~20 V Gate Driver Voltage
- ♦ 3.3 V,5V and 15 V logic compatible
- Vs Pin Can Withstand Maximum -5V Continuously
- Built-In 120ns Dead Time
- High and Low Side Output Interlock Function
- SOP-8 Package

Applications

- Motor Driver
- Air Conditioners/Washing Machines
- General Purpose Inverters
- Industrial Control
- Micro/Mini Inverter Drivers

General Description

SP6030F is a high-voltage half-bridge gate driver chip, which is suitable for bridge circuit design composed of double N-MOS or IGBT. It can be widely used in DC brushless motor drive schemes.

The SP6030F controls the output of the high-low drive circuit through two independent input signals. The built-in 120ns dead time and direct drive protection logic of the chip can prevent the external two power tubes from being switched on at the same time. The floating channel can be used to drive an N-channel power MOSFET in the high-side configuration which operates up to 600 V.

Simplified Application



Figure 1 Typical Application of SP6030F



Pin Function Description



Figure 2 Pin Configuration

Pin No.	Pin Name	Function Description
1	VCC	Bias supply input. Power supply for the input logic side of the device and also low-side driver.
2	HIN	Logic input for high-side driver.
3	LIN	Low-side driver output.
4	СОМ	Logical ground
5	LO	Low side drive output signal
6	VS	Return for high-side floating supply
7	НО	High side drive output signal
8	VB	High side floating power port

Ordering and Marking Information





Absolute Maximum Ratings

Characteristics	Symbol	Rating	Units
High Side Floating Supply Voltage	V_B	-0.3~650	V
High Side Floating Offset Voltage	Vs	V _B -25~V _B +0.3	V
High Side Gate Drive Output Voltage	V_{HO}	Vs-0.3~VB+0.3	V
Logic Power Supply Voltage	V _{CC}	-0.3~25	V
Logic Input Voltage of HIN/LIN	V _{IN}	-0.3~V _{CC} +0.3	V
Low Side Gate Drive Output Voltage	V_{LO}	-0.3~V _{CC} +0.3	V
Allowable Offset Supply Voltage Transient	dVs/dt	50	V/ns
Package Power Dissipation @ T_=25 $^\circ\!\mathrm{C}$	P _{DMAX}	0.625	W
Power Dissipation, PD @ $T_A=25^{\circ}C$	θ_{JA}	200	°C /W
Junction Temperature	TJ	-40~150	°C
Storage Temperature	T _{STG}	-55~150	°C

Note:

Note 1. Stresses listed as the above "Absolute Maximum Ratings" may cause permanent damage to the device. These are for stress ratings. Functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may remain possibility to affect device reliability.

Note 2. Devices are ESD sensitive. Handling precaution recommended.

Recommended Operating Conditions

Symbol	Description	Value	Units
V _B	High Side Floating Supply Voltage	V _S +10~V _S +20	V
Vs	High Side Floating Offset Voltage	-5~600	V
V _{но}	High Side Gate Drive Output Voltage	Vs~V _B	V
Vcc	Logic Power Supply Voltage	10~20	V
V _{IN}	Logic Input Voltage	0~15	V
Vlo	Low Side Gate Drive Output Voltage	0~V _{CC}	V
Тор	Operating Temperature Range	-40~85	°C
T _{LEAD}	Lead Temperature Range(Soldering 10sec)	260	°C

Note 1.All the above voltage parameters are based on COM. Without special explanation, T_A =25°C.



Block Diagram



Figure 3 Block Diagram of SP6030F

Sequence Chart









Figure 5 Time Parameter Definition



Electrical Characteristics

$V_{CC}=V_{BS}=15V$, VS=COM, unless otherwise specified

Characteristics	Symbol	Test Conditions	Min	Тур	Max	Units
Static Electrical Parameter						
V _{cc} Power Supply Threshold Voltage	V _{CC_ON}		7.5	8.4	9.2	V
V _{CC} Power Shutdown Threshold Voltage	V _{CC_OFF}		6.5	7.5	8.2	V
V _{CC} Undervoltage-Lockout	Vcc_uvlo		0.5	0.9	1.5	V
V _{BS} Power Supply Threshold Voltage	V _{BS_ON}		7.4	8.8	9.6	V
V _{BS} Power Shutdown Threshold Voltage	$V_{BS_{OFF}}$		6.4	7.8	8.6	V
V _{BS} Undervoltage-Lockout	Vbs_uvlo		0.5	1	1.5	V
V_{S} Maximum Static Negative Voltage	V_{SQN}	V _{BS} =15V			-5.0	V
Quiescent V _{CC} supply current	I _{QCC}	HIN=LIN=0V		52	75	μA
Quiescent V _{BS} supply current	I _{QBS}	HIN=LIN=0V		36	55	μA
Floating Power Leakage Current	I _{LK}	$V_{BS}=V_{S}=620V$			2	μA
Logic High Level Input Voltage	V _{IN+}			1.9		V
Logic Low Level Input Voltage	V _{IN-}			1.2		V
Logic High Level Input Current	I _{IN+}	HIN or LIN=5V		33	85	μA
Logic Low Level Input Current	I _{IN-}	HIN or LIN=0.2V			9.0	μA
High level output voltage (V_B - V_O)	V _{OUT+}	IO=20mA			0.5	V
Low level output voltage	V _{OUT-}	IO=20mA			0.5	V
High Lovel Output Short Circuit Dulas	I _{OUT+}	VO=0V				
		(VIN=5V,Short-circuit		450		mA
Current		Pulse Width<10us)				
Low Lovel Output Short Circuit Pulse		VO=15V				
Current	I _{OUT-}	(VIN=0V,Short-circuit		1000		mA
Current		Pulse Width<10us)				
Dynamic Electrical Parameter (CL=1nF)						
Turn On Transmission Delay	t _{on}	V _S =0V		250		ns
Turn Off Transmission Delay	t _{OFF}	V _S =0V or 600V		150		ns
Turn On Rising Time	tr			40		ns
Turn Off Falling Time	t _f			12		ns
Dead Time	DT			120		ns
High & Low Side Delay Matching Time	МТ	ton(HO)-ton(LO)			00	20
Thigh & Low Side Delay Matching Time		t _{OFF} (HO)-t _{OFF} (LO)			00	115

Note 1. The electrical parameter table defines the operating range of the device, whose maximum and minimum values are guaranteed by actual testing, and whose typical values are guaranteed by design values, performance and statistical analysis.

Note 2. The dynamic transmission time is greatly affected by the parasitic parameters of the peripheral track, and the actual test data shall prevail when used.



Typical Temperature Characteristic Curve





Package Information (Units: mm)



Cumbral	Dimensions in Millimeters			
Symbol	Min.	Nom.	Max.	
A	-	-	1.75	
A1	0.10	-	0.25	
A2	1.30	1.40	1.60	
A3	0.60	0.65	0.70	
D	4.70	4.90	5.10	
E	5.80	6.00	6.20	
E1	3.70	3.90	4.10	
b	0.39	-	0.48	
С	0.20	-	0.24	
e	1.27BSC			
h	0.25	-	- 0.50	
L	0.50	-	0.80	
L1	1.05BSC			
θ	0	-	8°	



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